

IN THE UNITED STATES
PATENT AND TRADEMARK OFFICE

Patent Application

Inventors(s): Stanley Pau
Donald Milan Tennant **Case:** 13-16

Serial No.: **Group Art Unit:** Not assigned yet

Filing Date: **Examiner:** Not assigned yet

Title: Focusable and Steerable Micro-miniature X-ray Apparatus

THE COMMISSIONER OF PATENTS AND TRADEMARKS
WASHINGTON, DC 20231

SIR:

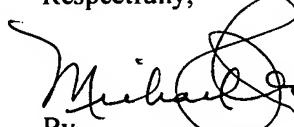
INFORMATION DISCLOSURE STATEMENT

In accordance with 37 CFR 1.97(b), the enclosed Information Disclosure Statement (IDS) is submitted for consideration in the above-identified application.

Copies of the reference(s) listed in the IDS are enclosed.

NO FEE IS REQUIRED.

Respectfully,


By _____

Michael J. Urbano
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610-691-7710

Date: 11/18/03

Att. IDS with reference(s)

APPLICANT: Stanley Pau et al.

INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

FILING DATE

GROUP

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB-CLASS	FILING DATE IF APPROPRIATE
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AA	4 3 4 0 2 8 3	7/82	Cohen	351	161	
AB	5 6 2 8 6 5 9	5/97	Xie et al.	445	3	
AC	6 1 4 8 0 6 1	11/00	Shefer et al.	378	121	
AD	6 2 5 9 7 6 4	7/01	Evans-Lutterodt et al.	378	84	
AE	6 4 4 8 1 0 0	9/02	Schulte et al.	438	20	
AF	6 4 7 7 2 3 3	11/02	Ribbing et al.	378	136	
AG	6 5 9 2 5 2 6	7/03	Lenker	600	463	
AH						
AI						
AJ						
AK						

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY/AUTHOR	CLASS	SUB-CLASS	TRANSL'N YES NO
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AL						
AM						
AN						
AO						
AP						

OTHER (Including Author, Title, Date, Pertinent Pages, Etc.)

AR	Henke et al., <i>Two-channel, elliptical...</i> , Rev. Sci. Instrum., Vol. 56, No. 8, p. 1537 (Aug. 1985)
AS	Lee et al., <i>High aspect ratio...</i> , J. Vac. Sci. Tech., Vol. B12, No. 6, p. 3425 (Nov/Dec. 1994)
AT	Tang et al., <i>Emission measurements...</i> , J. Vac. Sci. Tech., Vol. B14, No. 6, p. 3455 (Nov/Dec. 1996)
AU	Nagao et al., <i>Metal-oxide-semiconductor...</i> , J. Vac. Sci. Tech., Vol. B21, No. 1, p. 495 (Jan/Feb. 2003)
AV	Busta et al., <i>Characterization of electron...</i> , J. Vac. Sci. Tech., Vol. B21, No. 1, p. 344 (Jan/Feb. 2003)
AW	Evans-Lutterodt et al., <i>Single-element...</i> , Optics Express, Vol. 11, No. 8, p. 919 (Apr. 2003)
AX	

EXAMINER:

DATE CONSIDERED:

SHEET 1 OF 1